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TECHNICAL SPECIFICATION



Electrical insulating materials and systems – Electrical measurement of partial discharges (PD) under short rise time and repetitive voltage impulses

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTRICAL INSULATING MATERIALS AND SYSTEMS – ELECTRICAL MEASUREMENT OF PARTIAL DISCHARGES (PD) UNDER SHORT RISE TIME AND REPETITIVE VOLTAGE IMPULSES

FOREWORD

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This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition IEC TS 61934:2011. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

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IEC TS 61934 has been prepared by IEC technical committee 112: Evaluation and qualification of electrical insulating materials and systems. It is a Technical Specification.

This third edition cancels and replaces the second edition published in 2011. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) background information on the progress being made in the field of power electronics including the introduction of wide band gap semiconductor devices has been added to the Introduction;
- b) voltage impulse generators; the parameter values of the voltage impulse waveform have been modified to reflect application of wide band gap semiconductor devices.
- c) PD detection methods; charge-based measurements are not described in this third edition nor are source-controlled gating techniques to suppress external noise.
- d) Since the previous edition in 2011, there have been significant technical advances in this field as evidenced by several hundreds of publications. Consequently, the Bibliography in the 2011 edition has been deleted in this third edition.

The text of this Technical Specification is based on the following documents:

Draft	Report on voting
112/578/DTS	112/610/RVDTS

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

Power electronics has been developed along with both control theory and semiconductor technology. Switching is one of the essential features of power electronics control. For higher efficiency and smoother operation, switching times of the latest devices such as an insulated-gate bipolar transistor (IGBT) tend to be shorter than microseconds. The introduction of wide band gap devices, such as those based on silicon carbide, can result in transients with rise times of the order of a few tens of nanoseconds. Such a short rise time may can cause transient overvoltage impulses or surges in systems. When the voltage impulses reach the breakdown strength of an air gap, partial discharge (PD) may can occur. In addition, the impulses are repetitive from power electronics modulation such as pulse width modulation (PWM). Since PD may can cause degradation of electrical insulation parts in the system, it is one of the most important parameters to be measured.

The first edition of IEC TS 61934 was issued in April 2006. Because of rapid development in this field, the revision activity for the latest information was approved by TC 112 at their Berlin meeting in September 2006. In addition to technical and editorial changes, practical experience obtained through round-robin test (RRT) is also presented in Annex C. The second edition of IEC TS 61934 was published in 2011. Owing to further advances in this area, a revision of the second edition was commenced formally in 2019 and has resulted in this third edition.

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ELECTRICAL INSULATING MATERIALS AND SYSTEMS – ELECTRICAL MEASUREMENT OF PARTIAL DISCHARGES (PD) UNDER SHORT RISE TIME AND REPETITIVE VOLTAGE IMPULSES

1 Scope

This document is applicable to the off-line electrical measurement of partial discharges (PDs) that occur in electrical insulation systems (EISs) when stressed by repetitive voltage impulses generated from <u>electronic</u> power electronics devices.

Typical applications are EISs belonging to apparatus driven by power electronics, such as motors, inductive reactors and windmill, wind turbine generators and the power electronics modules themselves.

NOTE-1 Use of this document with specific products may can require the application of additional procedures.

NOTE 2 The procedures described in this technical specification are emerging technologies. Experience and caution, as well as certain preconditions, are needed to apply it.

Excluded from the scope of this document are

- methods based on optical or ultrasonic PD detection,
- fields of application for PD measurements when stressed by non-repetitive impulse voltages such as lightning impulse or switching impulses from switchgear.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60034 (all parts), Rotating electrical machines

IEC 60270:2000, High-voltage test techniques – Partial discharge measurements



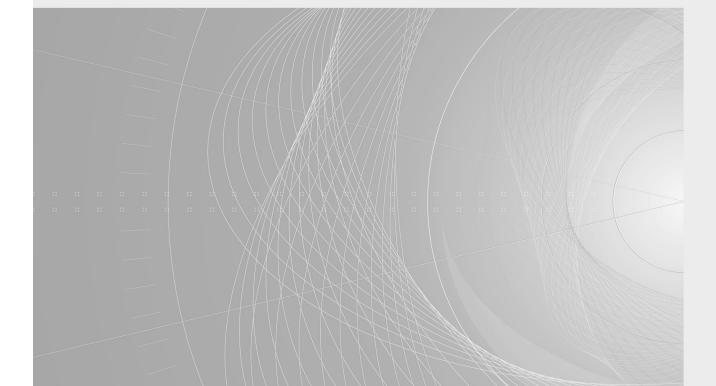
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TECHNICAL SPECIFICATION



Electrical insulating materials and systems – Electrical measurement of partial discharges (PD) under short rise time and repetitive voltage impulses



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTRICAL INSULATING MATERIALS AND SYSTEMS – ELECTRICAL MEASUREMENT OF PARTIAL DISCHARGES (PD) UNDER SHORT RISE TIME AND REPETITIVE VOLTAGE IMPULSES

FOREWORD

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IEC TS 61934 has been prepared by IEC technical committee 112: Evaluation and qualification of electrical insulating materials and systems. It is a Technical Specification.

This third edition cancels and replaces the second edition published in 2011. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) background information on the progress being made in the field of power electronics including the introduction of wide band gap semiconductor devices has been added to the Introduction;
- b) voltage impulse generators; the parameter values of the voltage impulse waveform have been modified to reflect application of wide band gap semiconductor devices.
- c) PD detection methods; charge-based measurements are not described in this third edition nor are source-controlled gating techniques to suppress external noise.

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d) Since the previous edition in 2011, there have been significant technical advances in this field as evidenced by several hundreds of publications. Consequently, the Bibliography in the 2011 edition has been deleted in this third edition.

The text of this Technical Specification is based on the following documents:

Draft	Report on voting
112/578/DTS	112/610/RVDTS

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

Power electronics has been developed along with both control theory and semiconductor technology. Switching is one of the essential features of power electronics control. For higher efficiency and smoother operation, switching times of devices such as an insulated-gate bipolar transistor (IGBT) tend to be shorter than microseconds. The introduction of wide band gap devices, such as those based on silicon carbide, can result in transients with rise times of the order of a few tens of nanoseconds. Such a short rise time can cause transient overvoltage impulses or surges in systems. When the voltage impulses reach the breakdown strength of an air gap, partial discharge (PD) can occur. In addition, the impulses are repetitive from power electronics modulation such as pulse width modulation (PWM). Since PD can cause degradation of electrical insulation parts in the system, it is one of the most important parameters to be measured.

The first edition of IEC TS 61934 was issued in April 2006. Because of rapid development in this field, the revision activity for the latest information was approved by TC 112 at their Berlin meeting in September 2006. The second edition of IEC TS 61934 was published in 2011. Owing to further advances in this area, a revision of the second edition was commenced formally in 2019 and has resulted in this third edition.

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ELECTRICAL INSULATING MATERIALS AND SYSTEMS – ELECTRICAL MEASUREMENT OF PARTIAL DISCHARGES (PD) UNDER SHORT RISE TIME AND REPETITIVE VOLTAGE IMPULSES

1 Scope

This document is applicable to the off-line electrical measurement of partial discharges (PDs) that occur in electrical insulation systems (EISs) when stressed by repetitive voltage impulses generated from power electronics devices.

Typical applications are EISs belonging to apparatus driven by power electronics, such as motors, inductive reactors, wind turbine generators and the power electronics modules themselves.

NOTE Use of this document with specific products can require the application of additional procedures.

Excluded from the scope of this document are

- methods based on optical or ultrasonic PD detection,
- fields of application for PD measurements when stressed by non-repetitive impulse voltages such as lightning impulse or switching impulses from switchgear.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60270, High-voltage test techniques – Partial discharge measurements